

Vaclav Holy

List of Publications by Year in descending order

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365
papers

9,520
citations

70961

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82
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371
all docs

371
docs citations

371
times ranked

8663
citing authors

#	ARTICLE	IF	CITATIONS
1	Structural properties of self-organized semiconductor nanostructures. <i>Reviews of Modern Physics</i> , 2004, 76, 725-783.	16.4	743
2	Nonspecular x-ray reflection from rough multilayers. <i>Physical Review B</i> , 1994, 49, 10668-10676.	1.1	497
3	A spin-valve-like magnetoresistance of an antiferromagnet-based tunnel junction. <i>Nature Materials</i> , 2011, 10, 347-351.	13.3	485
4	Self-Organized Growth of Three- Dimensional Quantum-Dot Crystals with fcc-Like Stacking and a Tunable Lattice Constant. , 1998, 282, 734-737.		433
5	High-Resolution X-Ray Scattering. <i>Advanced Texts in Physics</i> , 2004, , .	0.5	364
6	X-ray reflection from rough layered systems. <i>Physical Review B</i> , 1993, 47, 15896-15903.	1.1	268
7	Strain Induced Vertical and Lateral Correlations in Quantum Dot Superlattices. <i>Physical Review Letters</i> , 1999, 83, 356-359.	2.9	246
8	Interaction between graphene and copper substrate: The role of lattice orientation. <i>Carbon</i> , 2014, 68, 440-451.	5.4	180
9	Three-Dimensional Si/Ge Quantum Dot Crystals. <i>Nano Letters</i> , 2007, 7, 3150-3156.	4.5	175
10	Multiple-stable anisotropic magnetoresistance memory in antiferromagnetic MnTe. <i>Nature Communications</i> , 2016, 7, 11623.	5.8	169
11	Tuning of Vertical and Lateral Correlations in Self-Organized PbSe/Pb _{1-x} EuxTe Quantum Dot Superlattices. <i>Physical Review Letters</i> , 2000, 84, 4669-4672.	2.9	140
12	Magnetic properties of the CrMnFeCoNi high-entropy alloy. <i>Physical Review B</i> , 2017, 96, .	1.1	124
13	Tetragonal phase of epitaxial room-temperature antiferromagnet CuMnAs. <i>Nature Communications</i> , 2013, 4, 2322.	5.8	123
14	High-resolution x-ray diffraction from multilayered self-assembled Ge dots. <i>Physical Review B</i> , 1997, 55, 15652-15663.	1.1	117
15	Controlled Aggregation of Magnetic Ions in a Semiconductor: An Experimental Demonstration. <i>Physical Review Letters</i> , 2008, 101, 135502.	2.9	106
16	Nonmagnetic band gap at the Dirac point of the magnetic topological insulator (Bi _{1-x} Mnx) ₂ Se ₃ . <i>Nature Communications</i> , 2016, 7, 10559.	5.8	102
17	X-ray double and triple crystal diffractometry of mosaic structure in heteroepitaxial layers. <i>Journal of Applied Physics</i> , 1993, 74, 1736-1743.	1.1	84
18	Skin Layer of BiFeO_3 Crystals. <i>Physical Review Letters</i> , 2011, 106, 236101.	2.9	79

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19	Lateral and vertical ordering in multilayered self-organized InGaAs quantum dots studied by high resolution x-ray diffraction. Applied Physics Letters, 1997, 70, 955-957.	1.5	78
20	Effect of overgrowth on shape, composition, and strain of SiGe islands on Si(001). Physical Review B, 2002, 66, .	1.1	74
21	Disentangling bulk and surface Rashba effects in ferroelectric In_2Te -GeTe. Physical Review B, 2016, 94, .	1.1	74
22	Magnetostrictive thin films for microwave spintronics. Scientific Reports, 2013, 3, 2220.	1.6	73
23	Growth, Structure, and Electronic Properties of Epitaxial Bismuth Telluride Topological Insulator Films on BaF_2 (111) Substrates. Crystal Growth and Design, 2013, 13, 3365-3373.	1.4	70
24	Coplanar and grazing incidence x-ray-diffraction investigation of self-organized SiGe quantum dot multilayers. Physical Review B, 1998, 58, 7934-7943.	1.1	67
25	Magnetization reversal assisted by the inverse piezoelectric effect in Co-Fe-B ferroelectric multilayers. Physical Review B, 2011, 84, .	1.1	67
26	Strain-induced nonsymmorphic symmetry breaking and removal of Dirac semimetallic nodal line in an orthoperovskite iridate. Physical Review B, 2016, 93, .	1.1	67
27	X-ray Nanodiffraction on a Single SiGe Quantum Dot inside a Functioning Field-Effect Transistor. Nano Letters, 2011, 11, 2875-2880.	4.5	65
28	Local control of magnetocrystalline anisotropy in (Ga,Mn)As microdevices: Demonstration in current-induced switching. Physical Review B, 2007, 76, .	1.1	63
29	Strain and composition distribution in uncapped SiGe islands from x-ray diffraction. Applied Physics Letters, 2001, 79, 1474-1476.	1.5	62
30	Grazing-incidence small-angle X-ray scattering: application to the study of quantum dot lattices. Acta Crystallographica Section A: Foundations and Advances, 2012, 68, 124-138.	0.3	61
31	Formation of three-dimensional quantum-dot superlattices in amorphous systems: Experiments and Monte Carlo simulations. Physical Review B, 2009, 79, .	1.1	57
32	Grazing-incidence diffraction from multilayers. Physical Review B, 1995, 51, 16848-16859.	1.1	55
33	Demonstration of molecular beam epitaxy and a semiconducting band structure for I-Mn-V compounds. Physical Review B, 2011, 83, .	1.1	55
34	Vertical and lateral ordering in self-organized quantum dot superlattices. Physica E: Low-Dimensional Systems and Nanostructures, 2001, 9, 149-163.	1.3	54
35	Elastic strains in GaAs/AlAs quantum dots studied by high-resolution x-ray diffraction. Physical Review B, 1995, 52, 8348-8357.	1.1	53
36	Picosecond inverse magnetostriction in galphenol thin films. Applied Physics Letters, 2013, 103, .	1.5	52

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37	Magnetic anisotropy in antiferromagnetic hexagonal MnTe. <i>Physical Review B</i> , 2017, 96, .	1.1	49
38	Structural Investigations of Core-shell Nanowires Using Grazing Incidence X-ray Diffraction. <i>Nano Letters</i> , 2009, 9, 1877-1882.	4.5	47
39	The Coherence Description of the Dynamical X-ray Diffraction from Randomly Disordered Crystals I. General Formalism. <i>Physica Status Solidi (B): Basic Research</i> , 1982, 111, 341-351.	0.7	46
40	Current-induced torques in structures with ultrathin IrMn antiferromagnets. <i>Physical Review B</i> , 2015, 92, .	1.1	46
41	Diffuse x-ray scattering from misfit dislocations in SiGe epitaxial layers with graded Ge content. <i>Journal of Applied Physics</i> , 1995, 78, 5013-5021.	1.1	42
42	Dynamical X-ray diffraction from crystals with precipitates. I. Theory of the Bragg case. <i>Acta Crystallographica Section A: Foundations and Advances</i> , 1984, 40, 675-679.	0.3	41
43	Self-assembled carbon-induced germanium quantum dots studied by grazing-incidence small-angle x-ray scattering. <i>Applied Physics Letters</i> , 1999, 74, 3785-3787.	1.5	40
44	X-ray triple-crystal diffractometry of defects in epitaxial layers. <i>Journal of Applied Crystallography</i> , 1994, 27, 551-557.	1.9	39
45	Diffuse x-ray reflection from multilayers with stepped interfaces. <i>Physical Review B</i> , 1997, 55, 9960-9968.	1.1	39
46	The Coherence Description of the Dynamical X-ray Diffraction from Randomly Disordered Crystals II. Some Numerical Results. <i>Physica Status Solidi (B): Basic Research</i> , 1982, 112, 161-169.	0.7	38
47	Dyson and Bethe-Salpeter equations for dynamical X-ray diffraction in crystals with randomly placed defects. <i>Physica Status Solidi (B): Basic Research</i> , 1987, 140, 39-50.	0.7	38
48	X-ray Analysis of Structural Defects in a Semiconductor Superlattice. <i>Physica Status Solidi (B): Basic Research</i> , 1990, 162, 347-361.	0.7	38
49	X-ray diffuse scattering from threading dislocations in epitaxial GaN layers. <i>Journal of Applied Physics</i> , 2010, 108, 043521.	1.1	38
50	A complex study of the fast blue luminescence of oxidized silicon nanocrystals: the role of the core. <i>Nanoscale</i> , 2014, 6, 3837.	2.8	38
51	Ultrafast changes of magnetic anisotropy driven by laser-generated coherent and noncoherent phonons in metallic films. <i>Physical Review B</i> , 2016, 93, .	1.1	38
52	Structure and composition of bismuth telluride topological insulators grown by molecular beam epitaxy. <i>Journal of Applied Crystallography</i> , 2014, 47, 1889-1900.	1.9	36
53	On the Integrated Intensity of X-ray Diffraction in Crystals with Randomly Distributed Defects. <i>Physica Status Solidi (B): Basic Research</i> , 1989, 151, 23-28.	0.7	35
54	Oblique roughness replication in strained SiGe/Si multilayers. <i>Physical Review B</i> , 1998, 57, 12435-12442.	1.1	35

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55	Effect of overgrowth temperature on shape, strain, and composition of buried Ge islands deduced from x-ray diffraction. Applied Physics Letters, 2003, 82, 2251-2253.	1.5	35
56	The influence of deposition temperature on the correlation of Ge quantum dot positions in amorphous silica matrix. Nanotechnology, 2009, 20, 085612.	1.3	35
57	Powder diffraction in Bragg-Brentano geometry with straight linear detectors. Journal of Applied Crystallography, 2015, 48, 613-618.	1.9	35
58	Coherence Properties of Dynamically Diffracted X-Rays. Physica Status Solidi (B): Basic Research, 1980, 101, 575-583.	0.7	34
59	X-Ray Reflection Curves of Si Crystals with Microdefects in the Laue Case. Physica Status Solidi (B): Basic Research, 1987, 141, 35-45.	0.7	34
60	Grazing incidence small-angle x-ray scattering study of buried and free-standing SiGe islands in a SiGe/Si superlattice. Physical Review B, 2000, 62, 7229-7236.	1.1	34
61	Triple crystal x-ray diffractometry of periodic arrays of semiconductor quantum wires. Applied Physics Letters, 1993, 63, 3140-3142.	1.5	33
62	Structural and electronic properties of manganese-doped Bi ₂ Te ₃ epitaxial layers. New Journal of Physics, 2015, 17, 013028.	1.2	33
63	Vacancies in SnSe single crystals in a near-equilibrium state. Physical Review B, 2019, 99, .	1.1	33
64	Crystal structures and phase transitions of the van der Waals ferromagnet V ₃ I ₃ . Physical Review Materials, 2019, 3, .	0.9	33
65	Characterization of Microdefects in Silicon by Means of X-Ray Reflection Curves. Physica Status Solidi (B): Basic Research, 1989, 155, 339-347.	0.7	31
66	Analysis of strain and mosaicity in a short-period Si ₉ Ge ₆ superlattice by x-ray diffraction. Applied Physics Letters, 1994, 64, 172-174.	1.5	31
67	Ordered array of I° particles in Ti matrix studied by small-angle X-ray scattering. Acta Materialia, 2014, 81, 71-82.	3.8	30
68	Theoretical Description of Multiple Crystal Arrangements. NATO ASI Series Series B: Physics, 1996, , 259-268.	0.2	29
69	Unit cell structure of the wurtzite phase of GaP nanowires: X-ray diffraction studies and density functional theory calculations. Physical Review B, 2013, 88, .	1.1	28
70	Twin domain imaging in topological insulator Bi ₂ Te ₃ and Bi ₂ Se ₃ epitaxial thin films by scanning X-ray nanobeam microscopy and electron backscatter diffraction. Journal of Applied Crystallography, 2017, 50, 369-377.	1.9	28
71	X-ray diffraction on Fibonacci superlattices. Acta Crystallographica Section A: Foundations and Advances, 1995, 51, 825-830.	0.3	27
72	Ge quantum dot lattices in Al ₂ O ₃ multilayers. Journal of Nanoparticle Research, 2013, 15, 1.	0.8	27

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91	X-ray interference effects on the determination of structural data in ultrathin La ₂ /3Sr ₁ /3MnO ₃ epitaxial thin films. Applied Physics Letters, 2011, 99, .	1.5	22
92	Structure and microstructure of Ni-Mn-Ga single crystal exhibiting magnetic shape memory effect analysed by high resolution X-ray diffraction. Acta Materialia, 2016, 115, 250-258.	3.8	22
93	Ferroelectric Self-Poling in GeTe Films and Crystals. Crystals, 2019, 9, 335.	1.0	22
94	Strain-induced self-organized growth of nanostructures: From step bunching to ordering in quantum dot superlattices. Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena, 2000, 18, 2187.	1.6	21
95	High-resolution x-ray diffraction from self-organized PbSe/PbEuTe quantum dot superlattices. Journal Physics D: Applied Physics, 2001, 34, A1-A5.	1.3	21
96	Grazing incidence small-angle x-ray scattering study of self-organized SiGe wires. Physical Review B, 2001, 63, .	1.1	21
97	Watching nanomaterials with X-ray eyes: Probing different length scales by combining scattering with spectroscopy. Progress in Materials Science, 2020, 112, 100667.	16.0	21
98	Scanning-tunneling-microscopy observation of stress-driven surface diffusion due to localized strain fields of misfit dislocations in heteroepitaxy. Physical Review B, 1996, 54, 4500-4503.	1.1	20
99	Lateral arrangement of self-assembled quantum dots in an SiGe/Si superlattice. Journal Physics D: Applied Physics, 1999, 32, A234-A238.	1.3	20
100	Lateral composition modulation in (InAs) _n /(AlAs) _m short-period superlattices investigated by high-resolution x-ray scattering. Physical Review B, 2002, 66, .	1.1	20
101	Influence of GaN domain size on the electron mobility of two-dimensional electron gases in AlGa _N /GaN heterostructures determined by x-ray reflectivity and diffraction. Applied Physics Letters, 2002, 80, 3521-3523.	1.5	20
102	Diffuse x-ray scattering from stacking faults in a -plane GaN epitaxial layers. Physical Review B, 2011, 84, .	1.1	20
103	Growth of Ti_3Sn inclusions in Ti alloys: An X-ray diffraction study. Acta Materialia, 2013, 61, 6635-6645.	3.8	20
104	Structural characterization of self-assembled quantum dot structures by X-ray diffraction techniques. Thin Solid Films, 1997, 306, 198-204.	0.8	19
105	Ordering parameters of self-organized three-dimensional quantum-dot lattices determined from anomalous x-ray diffraction. Applied Physics Letters, 2004, 84, 885-887.	1.5	19
106	Investigation of shape, strain, and interdiffusion in InGaAs quantum rings using grazing incidence x-ray diffraction. Journal of Applied Physics, 2006, 99, 033519.	1.1	19
107	Mn incorporation in as-grown and annealed (Ga,Mn)As layers studied by x-ray diffraction and standing-wave fluorescence. Physical Review B, 2006, 74, .	1.1	19
108	Diffuse x-ray scattering from statistically inhomogeneous distributions of threading dislocations beyond the ergodic hypothesis. Physical Review B, 2008, 77, .	1.1	19

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109	Self-assembled Mn ₅ Ge ₃ nanomagnets close to the surface and deep inside a Ge _{1-x} Mnx epilayer. Applied Physics Letters, 2009, 95, 023102.	1.5	19
110	Nano-structuring of solid surface by extreme ultraviolet Ar ⁸⁺ laser. Laser and Particle Beams, 2012, 30, 57-63.	0.4	19
111	Exploiting GISAXS for the Study of a 3D Ordered Superlattice of Self-Assembled Colloidal Iron Oxide Nanocrystals. Crystal Growth and Design, 2012, 12, 5505-5512.	1.4	19
112	Diffuse x-ray scattering from porous silicon by triple axis diffractometry. Applied Physics Letters, 1994, 65, 1504-1506.	1.5	18
113	Lateral and vertical ordering of self-assembled PbSe quantum dots studied by high-resolution X-ray diffraction. Physica B: Condensed Matter, 2000, 283, 65-68.	1.3	18
114	Defect Cores Investigated by X-Ray Scattering close to Forbidden Reflections in Silicon. Physical Review Letters, 2007, 99, 225504.	2.9	18
115	Magnetic and structural properties of Mn-doped Bi ₂ Se ₃ topological insulators. Physica B: Condensed Matter, 2016, 481, 262-267.	1.3	18
116	The influence of specular interface reflection on grazing incidence X-ray diffraction and diffuse scattering from superlattices. Physica B: Condensed Matter, 1994, 198, 249-252.	1.3	17
117	X-ray reflectivity investigations of the interface morphology in strained SiGe/Si multilayers. Semiconductor Science and Technology, 1998, 13, 590-598.	1.0	17
118	In situ investigations of Si and Ge interdiffusion in Ge-rich Si/SiGe multilayers using x-ray scattering. Semiconductor Science and Technology, 2007, 22, 447-453.	1.0	17
119	In situ x-ray scattering study on the evolution of Ge island morphology and relaxation for low growth rate: Advanced transition to superdomes. Physical Review B, 2009, 80, .	1.1	17
120	Structural and charge trapping properties of two bilayer (Ge+SiO ₂)/SiO ₂ films deposited on rippled substrate. Applied Physics Letters, 2010, 97, 163117.	1.5	17
121	Generation of an ordered Ge quantum dot array in an amorphous silica matrix by ion beam irradiation: Modeling and structural characterization. Physical Review B, 2010, 81, .	1.1	17
122	Single crystal growth of Ti-6Al-4V titanium alloy by a floating zone method. Journal of Crystal Growth, 2014, 405, 92-96.	0.7	17
123	X-ray diffractometry of small defects in layered systems. Journal Physics D: Applied Physics, 1993, 26, A146-A150.	1.3	16
124	X-ray Reflectometer for the Diagnostics of Thin Films During Growth. Journal of Applied Crystallography, 1997, 30, 905-908.	1.9	16
125	Highly regular self-organization of step bunches during growth of SiGe on Si(113). Applied Physics Letters, 1998, 73, 1535-1537.	1.5	16
126	Self-organized growth of three-dimensional III-V semiconductor quantum dot crystals with fcc-like vertical stacking and tunable lattice constant. Surface Science, 2000, 454-456, 657-670.	0.8	16

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127	Strain in buried self-assembled SiGe wires studied by grazing-incidence x-ray diffraction. Physical Review B, 2002, 65, .	1.1	16
128	Dot size dependence of vertical and lateral ordering in self-organized PbSe/Pb ^{1-x} EuxTe quantum-dot superlattices. Applied Physics Letters, 2003, 82, 799-801.	1.5	16
129	On the driving forces for the vertical alignment in nitride quantum dot multilayers. Europhysics Letters, 2003, 63, 268-274.	0.7	16
130	X-ray diffuse scattering from defects in nitrogen-doped Czochralski grown silicon wafers. Journal Physics D: Applied Physics, 2005, 38, A105-A110.	1.3	16
131	Design of quantum dot lattices in amorphous matrices by ion beam irradiation. Physical Review B, 2011, 84, .	1.1	16
132	Tuning luminescence properties of silicon nanocrystals by lithium doping. Journal of Applied Physics, 2012, 112, .	1.1	16
133	Obtaining the structure factors for an epitaxial film using Cu X-ray radiation. Journal of Applied Crystallography, 2013, 46, 1749-1754.	1.9	16
134	Production of three-dimensional quantum dot lattice of Ge/Si core-shell quantum dots and Si/Ge layers in an alumina glass matrix. Nanotechnology, 2015, 26, 065602.	1.3	16
135	Electronic and transport properties of the Mn-doped topological insulator Bi_2Te_3 : A first-principles study. Physical Review B, 2016, 93, .	1.6	16
136	The instrumental resolution of a moire extensometer in light of its recent automatisisation. Measurement: Journal of the International Measurement Confederation, 2016, 91, 258-265.	2.5	16
137	Density of bunched threading dislocations in epitaxial GaN layers as determined using X-ray diffraction. Journal of Applied Physics, 2018, 123, .	1.1	16
138	X-ray reflection curves of crystals with randomly distributed microdefects in the Bragg case. Acta Crystallographica Section A: Foundations and Advances, 1983, 39, 642-646.	0.3	15
139	Interface roughness in surface-sensitive X-ray methods. Journal Physics D: Applied Physics, 1995, 28, A220-A226.	1.3	15
140	Structural study of self-assembled Co nanoparticles. Journal of Applied Physics, 2003, 94, 7743.	1.1	15
141	Surface Exchange and Shape Transitions of PbSe Quantum Dots during Overgrowth. Physical Review Letters, 2006, 97, 266103.	2.9	15
142	Tracking defect type and strain relaxation in patterned Ge/Si(001) islands by x-ray forbidden reflection analysis. Physical Review B, 2011, 84, .	1.1	15
143	Lattice strain of hydrogen-implanted silicon: Correlation between X-ray scattering analysis and ab-initio simulations. Journal of Applied Physics, 2013, 113, 153511.	1.1	15
144	Self-Seeded Axio-Radial InAs _{1-x} P _x Nanowire Heterostructures beyond Common VLS Growth. Nano Letters, 2018, 18, 144-151.	4.5	15

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145	Determination of threading dislocation density in hetero-epitaxial layers by diffuse X-ray scattering. Journal Physics D: Applied Physics, 1995, 28, A114-A119.	1.3	14
146	X-ray scattering study of interface roughness correlation in Mo/Si and Ti/C multilayers for X-UV optics. Physica B: Condensed Matter, 1998, 253, 28-39.	1.3	14
147	High-resolution diffuse x-ray scattering from threading dislocations in heteroepitaxial layers. Applied Physics Letters, 2004, 85, 3065-3067.	1.5	14
148	Diffuse x-ray scattering from inclusions in ferromagnetic $\text{Ge}_{1-x}\text{Te}_x$. Physical Review B, 2008, 78, .	1.1	14
149	Crystallization kinetics study of cerium titanate CeTi_2O_6 . Journal of Physics and Chemistry of Solids, 2014, 75, 265-270.	1.9	14
150	Thermoelectric and magnetic properties of Cr-doped single crystal Bi_2Se_3 – Search for energy filtering. Journal of Solid State Chemistry, 2018, 258, 768-775.	1.4	14
151	The diffuse X-ray scattering in real periodical superlattices. Superlattices and Microstructures, 1992, 12, 25-35.	1.4	13
152	Self-organized ordering in self-assembled quantum dot superlattices. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2002, 88, 143-152.	1.7	13
153	Shape and composition change of Ge dots due to Si capping. Applied Surface Science, 2004, 224, 139-142.	3.1	13
154	X-ray diffuse scattering from stacking faults in Czochralski silicon. Semiconductor Science and Technology, 2006, 21, 352-357.	1.0	13
155	Nanometer-scale period Sc/Cr multilayer mirrors and their thermal stability. Thin Solid Films, 2006, 497, 115-120.	0.8	13
156	Strain control of magnetic anisotropy in $(\text{Ga},\text{Mn})\text{As}$ microbars. Physical Review B, 2011, 83, .	1.1	13
157	Complementary information on CdSe/ZnSe quantum dot local structure from extended X-ray absorption fine structure and diffraction anomalous fine structure measurements. Journal of Alloys and Compounds, 2012, 523, 155-160.	2.8	13
158	Study of threading dislocation density reduction in AlGaIn epilayers by Monte Carlo simulation of high-resolution reciprocal-space maps of a two-layer system. Journal of Applied Crystallography, 2013, 46, 120-127.	1.9	13
159	Complementary information on CdSe/ZnSe quantum dot local structure from extended X-ray absorption fine structure and diffraction anomalous fine structure measurements. Journal of Alloys and Compounds, 2012, 523, 155-160.	3.8	13
160	Ferroelectric phase transitions in multiferroic $\text{Ge}_{1-x}\text{Mn}_x\text{Te}$ driven by local lattice distortions. Physical Review B, 2016, 94, .	1.1	13
161	Influence of an Anomalous Temperature Dependence of the Phase Coherence Length on the Conductivity of Magnetic Topological Insulators. Physical Review Letters, 2019, 123, 036406.	2.9	13
162	Investigation of the growth striations in silicon by X-ray topography. European Physical Journal D, 1983, 33, 1315-1322.	0.4	12

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163	The Role of Diffuse Scattering on Microdefects in the Precise Lattice Parameter Measurement. <i>Physica Status Solidi (B): Basic Research</i> , 1988, 145, 363-372.	0.7	12
164	Local surface deformations induced by interfacial misfit dislocations in lattice-mismatched heteroepitaxy of EuTe on PbTe(111). <i>Surface Science</i> , 1996, 365, 453-460.	0.8	12
165	Thermal stability of $\text{W}^{1\text{st}}\text{Si}_6/\text{Si}$ multilayers under rapid thermal annealing. <i>Journal of Applied Physics</i> , 1997, 81, 2229-2235.	1.1	12
166	Detailed structural analysis of semiconductors with X-ray scattering. <i>Materials Science in Semiconductor Processing</i> , 2001, 4, 475-481.	1.9	12
167	X-ray reflectivity of self-assembled structures in SiGe multilayers and comparison with atomic force microscopy. <i>Journal of Applied Physics</i> , 2001, 89, 4836-4842.	1.1	12
168	$\text{Ge}\cdot\text{Si}$ islands in a three-dimensional island crystal studied by x-ray diffraction. <i>Journal of Applied Physics</i> , 2005, 98, 073517.	1.1	12
169	Shape and composition of buried PbSe quantum dots determined by scanning tunneling microscopy. <i>Applied Physics Letters</i> , 2007, 90, 113119.	1.5	12
170	Growth and characterization of stacking fault reduced GaN $(1,0,0)$ on sapphire. <i>Journal Physics D: Applied Physics</i> , 2013, 46, 125308.	1.3	12
171	X-ray rocking curves on inhomogeneous surface layers on Si single crystals. <i>European Physical Journal D</i> , 1982, 32, 750-766.	0.4	11
172	Structural properties of perfect ZnTe epilayers on (001) GaAs substrates. <i>Journal of Crystal Growth</i> , 1994, 138, 81-85.	0.7	11
173	Stacked Josephson junction based on Nb/Si superlattice. <i>Journal of Low Temperature Physics</i> , 1997, 106, 373-379.	0.6	11
174	X-ray studies on self-organized wires in SiGe/Si multilayers. <i>Journal Physics D: Applied Physics</i> , 2001, 34, A6-A10.	1.3	11
175	X-ray diffraction from CuPt-ordered III-V ternary semiconductor alloy films. <i>Physical Review B</i> , 2001, 63, .	1.1	11
176	Size and spatial homogeneity of SiGe quantum dots in amorphous silica matrix. <i>Journal of Applied Physics</i> , 2009, 106, 084319.	1.1	11
177	Scanning tunneling microscopy reveals LiMnAs is a room temperature anti-ferromagnetic semiconductor. <i>Applied Physics Letters</i> , 2012, 100, 112107.	1.5	11
178	Three-dimensional reciprocal space mapping of diffuse scattering for the study of stacking faults in semipolar $(1\bar{1}0)$ GaN layers grown from the sidewall of an $\langle 110 \rangle$ -patterned sapphire substrate. <i>Journal of Applied Crystallography</i> , 2013, 46, 1425-1433.	1.9	11
179	Strain relief and shape oscillations in site-controlled coherent SiGe islands. <i>Nanotechnology</i> , 2013, 24, 335707.	1.3	11
180	The electronic structure of homogeneous ferromagnetic (Ga, Mn)N epitaxial films. <i>Journal of Applied Physics</i> , 2015, 117, .	1.1	11

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181	Structure of epitaxial SrIrO ₃ perovskite studied by interference between X-ray waves diffracted by the substrate and the thin film. Journal of Applied Crystallography, 2017, 50, 385-398.	1.9	11
182	On the completeness of the $\beta_2 \rightarrow \beta_1$ transformation in metastable β_2 titanium alloys. Journal of Applied Crystallography, 2017, 50, 283-287.	1.9	11
183	Rapid floating zone growth of Ni ₂ MnGa single crystals exhibiting magnetic shape memory functionality. Journal of Alloys and Compounds, 2019, 775, 533-541.	2.8	11
184	High Resolution X-Ray Triple Axis Diffractometry of Short Period Superlattices. Japanese Journal of Applied Physics, 1994, 33, 2322-2328.	0.8	10
185	Strain relaxation and misfit dislocations in compositionally graded Si _{1-x} Ge _x layers on Si(001). Journal of Crystal Growth, 1995, 157, 137-141.	0.7	10
186	Structural characterization of self-assembled Ge dot multilayers by X-ray diffraction and reflectivity methods. Physica E: Low-Dimensional Systems and Nanostructures, 1998, 2, 789-793.	1.3	10
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